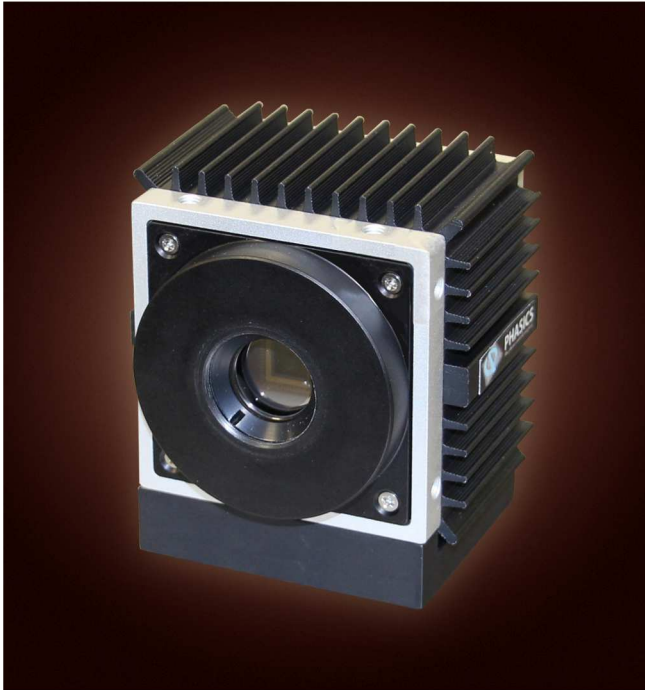


SID4 UV

WAVE FRONT SENSOR



↓ SPECIFICATIONS

Aperture dimension	7.4 x 7.4 mm ²
Spatial resolution	29.6 μm
Sampling	250 x 250
Wavelength range	250 - 400 nm
Accuracy (absolute)	10 nm RMS
Resolution (Phase)	2 nm RMS
Dynamic	> 200 μm PtV
Analysis rate	2 fps
Acquisition rate	30 fps
Computer connection	Ethernet
Dimensions (WxHxL)	45 x 30 x 100 mm
Weight	250 g

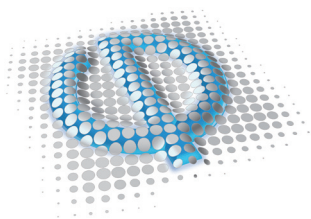
→ The **SID4-UV** wavefront sensor benefits from PHASICS patented technology*. It not only offers an unequalled high resolution (250x250 measurement points) but it is also compact and very easy-to-use. Thus it delivers **fast and accurate** measurement.

It is a cost-effective solution for **testing quality of UV optics** such as lens used in semiconductors systems (MTF, aberrations...). It also allows full **surface inspection** of lens, mirror, wafer...

The SID4-UV is an efficient instrument for ultraviolet **laser beam measurement** (Zernike coefficients, PSF, M², Strehl Ratio, beam profile...)

➤ KEY FEATURES

- Very high resolution: 250x250 phase pixels
- Large analysis pupil: 7.4 x 7.4 mm²
- Broadband
- Compact
- Cost-effective

**PHASICS S.A.**

Bâtiment Explorer
Espace Technologique
Route de l'Orme des Merisiers
91190 Saint-Aubin
FRANCE

Tel : +33(0)1 80 75 06 33

contact@phasics.fr

www.phasics.fr

PHASICS CORP.

600 California Street
11th Floor
San Francisco CA 94108
USA

Tel : +1 415 610 9741